

Claims

What is claimed is:

1. A probe card of a measuring apparatus for a semiconductor device comprising: an electrically-  
5 conductive linear probe needle whose bottom end contacts with the device under test, a circuit board with which the upper end of the probe needle is connected electrically, an upper guide plate held horizontally and firmly near the middle point between  
10 the upper end and the center of said probe needle and having a guide hole to guide said probe needle, a lower guide plate held horizontally and firmly near the middle point between the center and the bottom end of said probe needle and having a guide hole to guide said  
15 probe needle, a rotary guide plate held horizontally and movably near the center of said probe needle and having a guide hole to guide said probe needle, an initial-position holding means to hold said rotary guide plate temporary and firmly at the initial  
20 position where said probe needle is straight, a movable holding means to hold movably said rotary guide plate at the position where the center of said probe needle bent, a driving means to move said rotary guide plate in the horizontal plane.

25 2. The probe card as claimed in claim 1, wherein an arc-shaped guide slot is made in said rotary guide plate and said movable holding means is a fixed guide pin to be inserted in said guide hole.

30 3. The probe card as claimed in claim 1, wherein an eccentric bearing is mounted in said rotary guide plate and said movable holding means is the fixed guide pin inserted in said eccentric bearing.

35 4. The probe card as claimed in claim 1, wherein eccentric bearings are mounted in both of said upper and lower guide plates and said movable holding means

is the fixed guide pin fixed in said rotary guide plate and inserted in said eccentric bearings.

5           5. The probe card as claimed in claim 1, wherein said rotary guide plate has a stepped stage.

6           6. The probe card as claimed in claim 1, wherein the diameter of the probe needle for power supply is larger than the diameter of the probe needle for signal.

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